



TELEFUNKEN
Semiconductors




Integration of Disruptive Materials for Advanced Non-Volatile Memories

Wilbur Catabay

NCCAVS PAG User Group Meeting

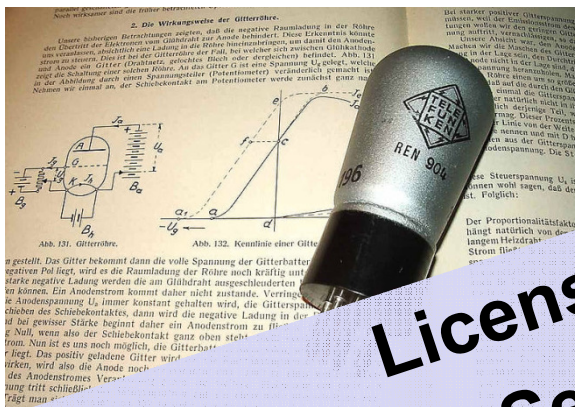
"Plasma Applications in Novel Materials Processing"

April 29, 2013



- TSI Semiconductor, TDCS Overview
- Non Volatile Memory Trends
- Solutions for NVM Memory Development
- Process Module Blocks
- Summary

- Who, What is “Telefunken”?
 - German radio and television apparatus company, founded in Berlin 1903



Telefunken REN 904. A vacuum tube used in early German radios.

Licensed the name “Telefunken”
Telefunken Semiconductor International LLC = TSI

Telefunken alarm clock from c. 1995, designed by Philippe Starck

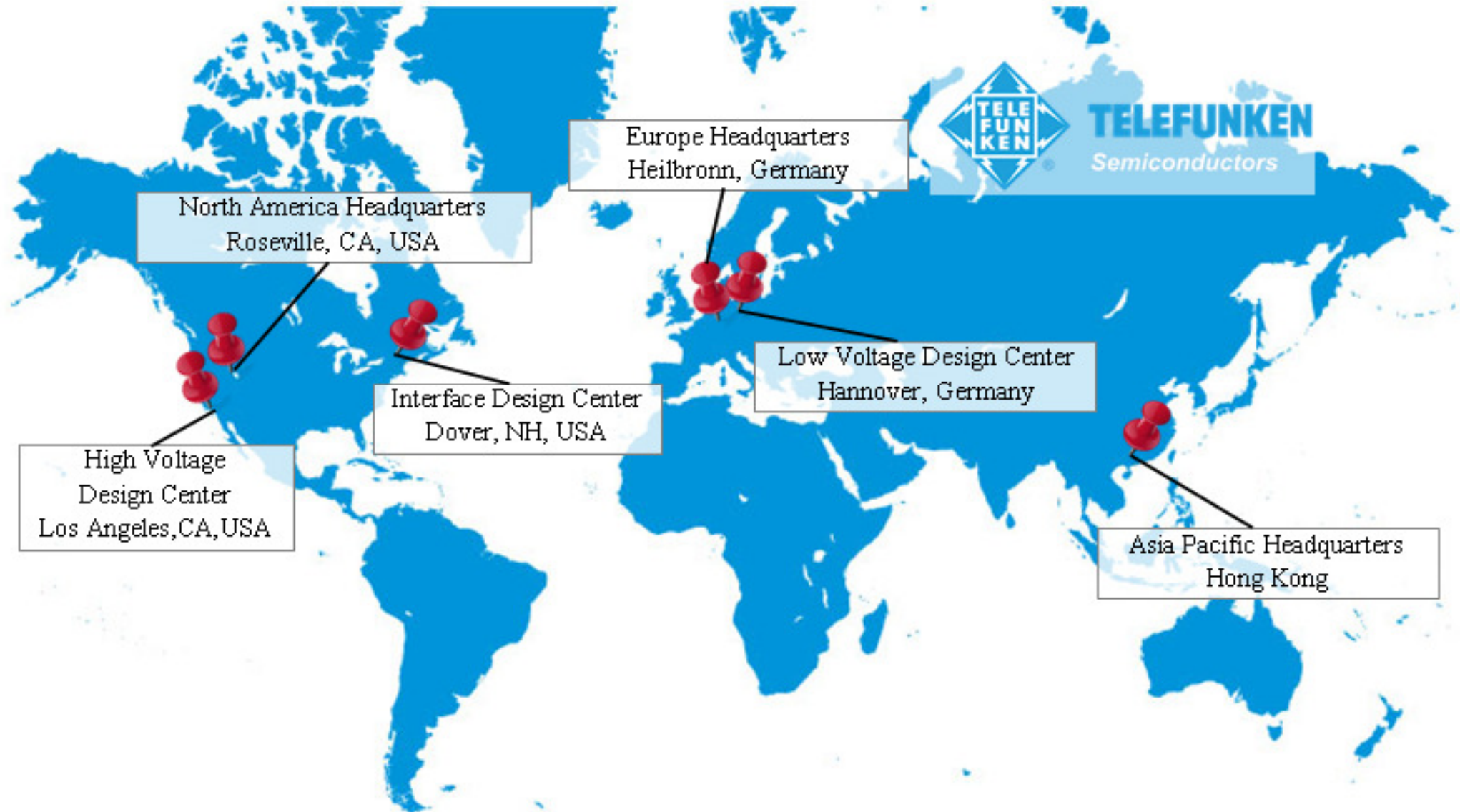


A modern Telefunken RC 881 cassette, CD player, and radio



Telefunken water boiling from 2011

TELEFUNKEN Semiconductors International is a US company & Incorporated in State of Delaware



World-Class Foundry Technologies in Smart-Power, Bipolar, High Voltage, Power MOSFET, IGBT, Embedded Flash, and High Frequency Platforms



Foundry, Heilbronn, Germany



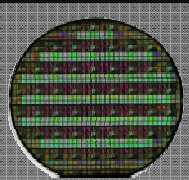
**Foundry & TDCS, Roseville, California
Corporate Headquarters**

TDCS – Technology Development & Commercialization Services

Our History

SPECIALIZED FOUNDRY SERVICES

NEC



5-inch
K-line
Production



6-inch
M-line
Production

1984

1987

1990



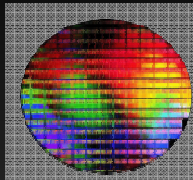
DRAM
Production
High Volume



ISO 9000
Certification

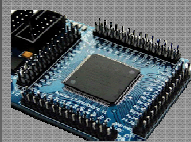


Automotive
Supplier



8-inch
M-line
Production

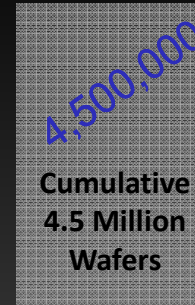
RENESAS



Memory,
μprocessor,
ASIC's



ISO 14001
Certification



Cumulative
4.5 Million
Wafers



ISO/TS
16949
Certification

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May 2011

TSI Semi acquires
Renesas Roseville
Manufacturing Facility

SVTC



TSI Semi
Acquires
SJ SVTC

for tool
extension

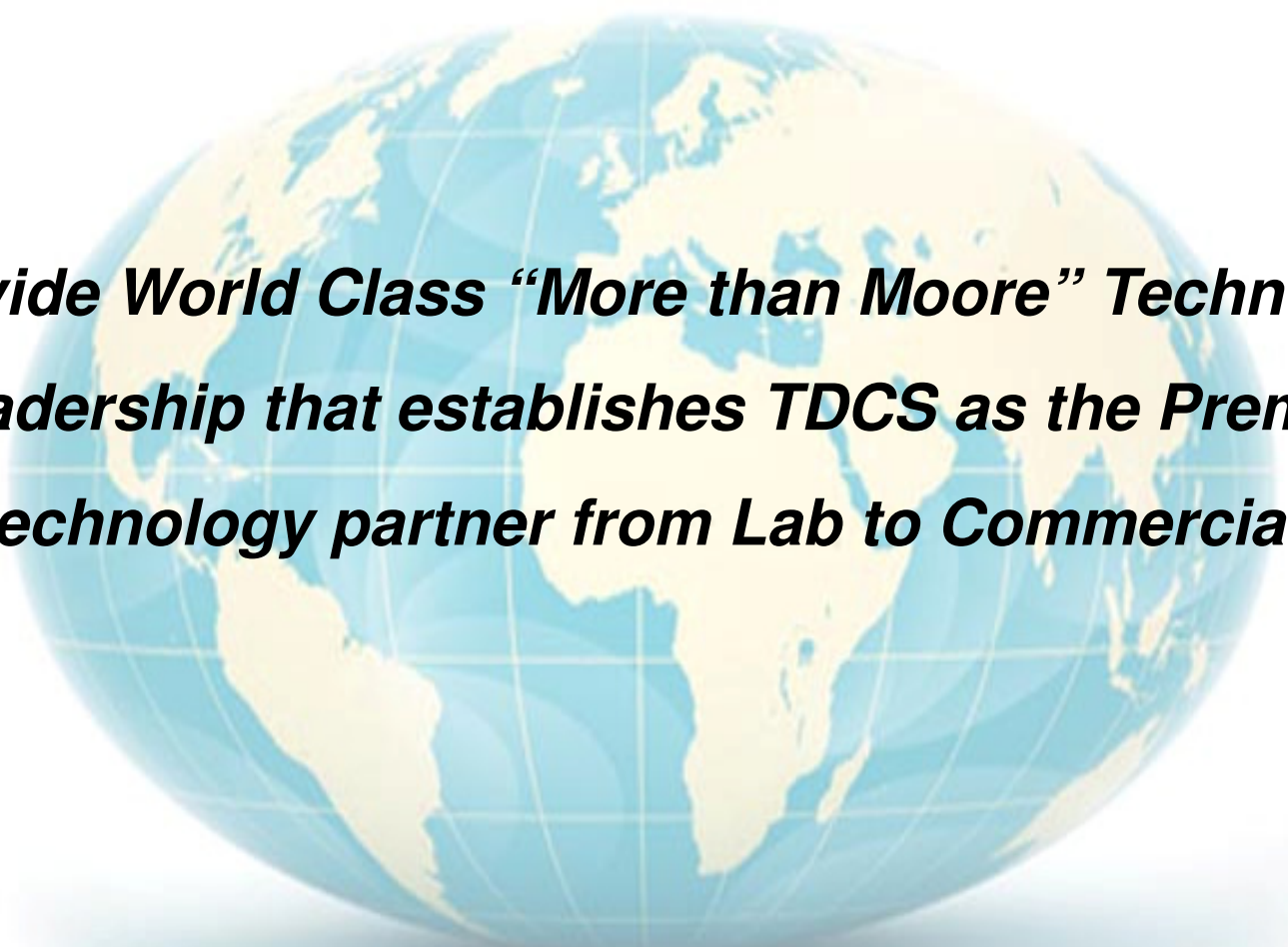


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Capabilities

- Production grade tools in Class 3 Clean Rooms
- 84,000 square feet of Fab Clean Room Space
- *Engineering Consultants and Program Managers*
- 24/7 Engineering, Operations & Maintenance
- Manufacturing Execution Systems (MES)
- IP Secure Environments
- Robust Quality Systems
- Automotive Registered
- Onsite Analytical Tools & Labs
- *Process Library*
- *Novel Materials*
- AlSiCu BEOL
- Lithography Capable to 110nm
- *Transparent Substrates*
- *Emerging Technology Capabilities*



Provide World Class “More than Moore” Technology leadership that establishes TDCS as the Premier Nanotechnology partner from Lab to Commercialization

TDCS provides Technology Development & Commercialization Services in an open and flexible environment.

Infrastructure Access

Access to robust infrastructure for development & manufacturing needs

- R&D Wafer Processing
- Tool Hosting/ Clean Room Rental
- Hands on Access
- Tool Access
- Office Facilities
- Process Library

Engineering

Utilize blended pool of engineering services to support development efforts

- Blended Engineering Pool
- Project Management
- Analytical Services

Manufacturing

Pilot & low volume production or process transfer services to high volume partners

- Custom Process Flows
- Fast Transfer Services
- PDK's for High Voltage, MXS, Analog Devices

Value Chain

Provide total solutions through a network of service and product partners

TOPPAN
TOPPAN PHOTOMASKS, INC.

entrepix
YOUR CMP PARTNER

MEMC
TECHNOLOGY IS BUILT ON US

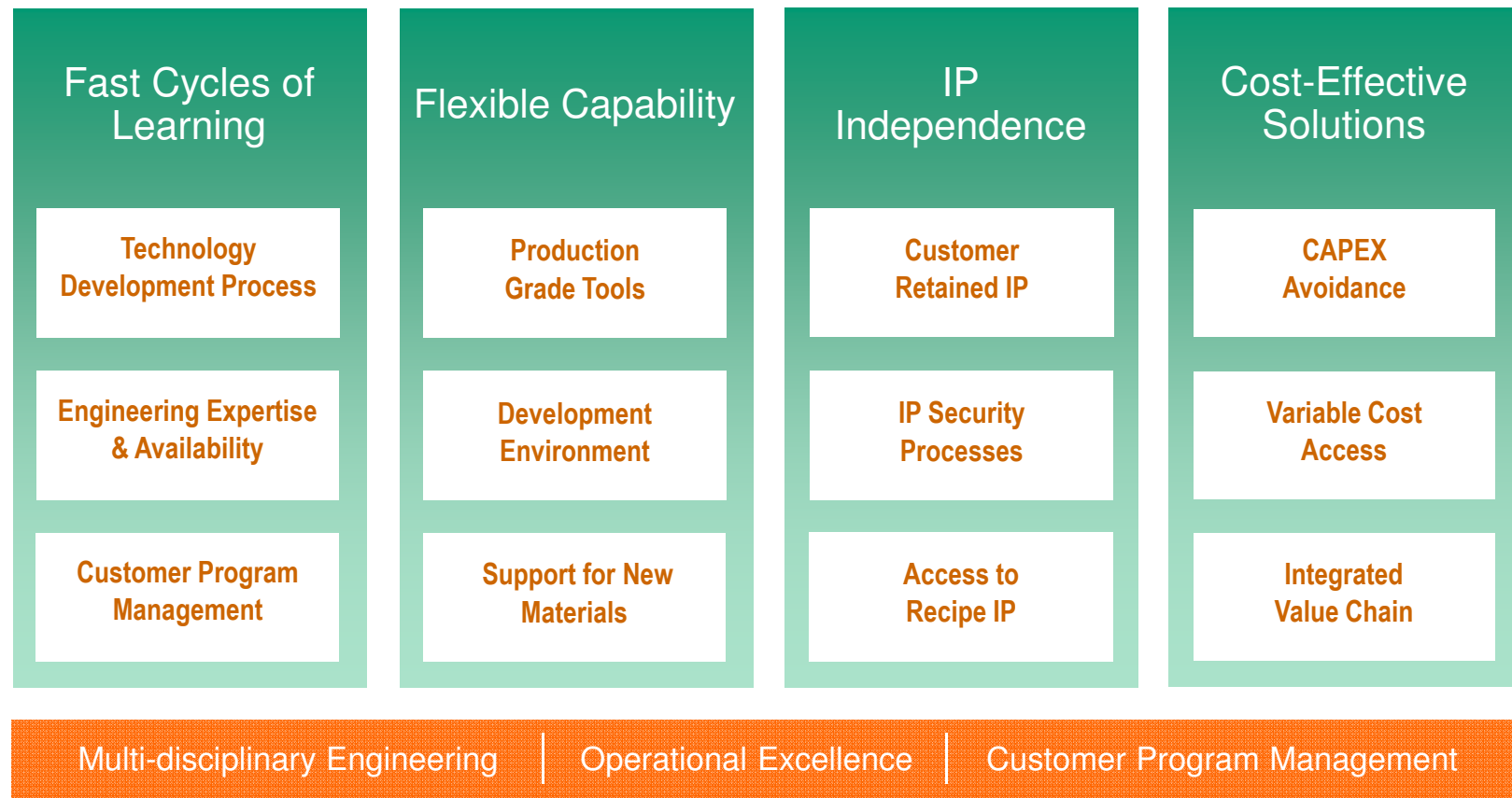
SINGULUS

CORWIL
TECHNOLOGY CORPORATION

SUSS MicroTec

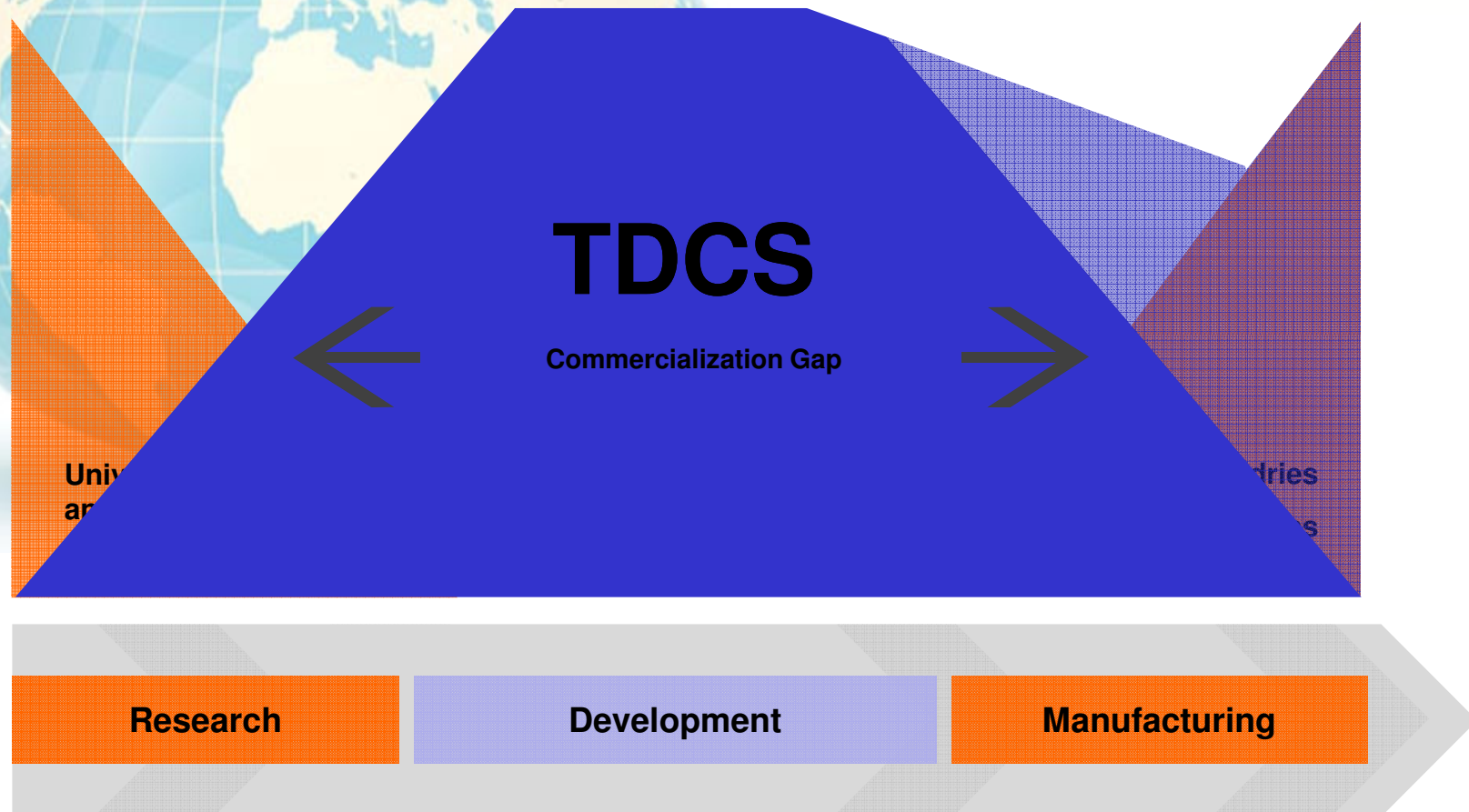


We create a collaborative relationship with customers to enable the fastest and most cost effective time to market for technology and product commercialization while enabling customer IP independence





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- TSI Semiconductor, TDCS Overview
- Non Volatile Memory Trends
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- Process Module Blocks
- Summary

- Mobile Applications
- Tablets
- SSD's

NAND Scaling Extends to 2015

Log Scale

— NAND Historical
— NAND Projection

2010

2015

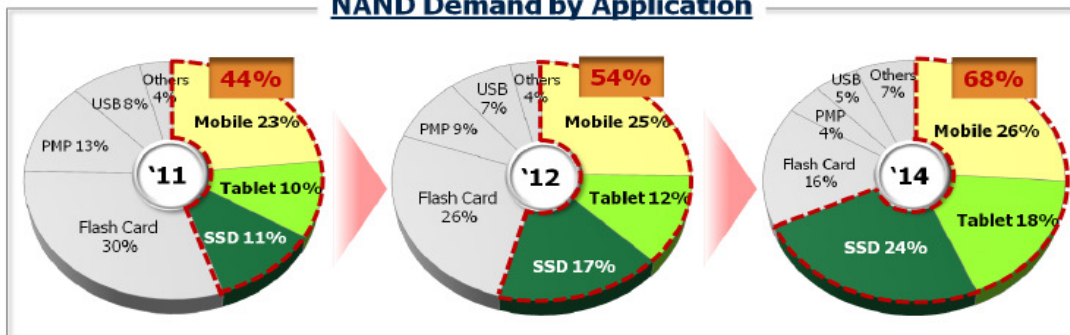
Source: SanDisk



Prospective Application Trend

Mobile, Tablet, SSD dominate NAND demand in 2011~2014

NAND Demand by Application



[Source; Hynix Marketing 2011]

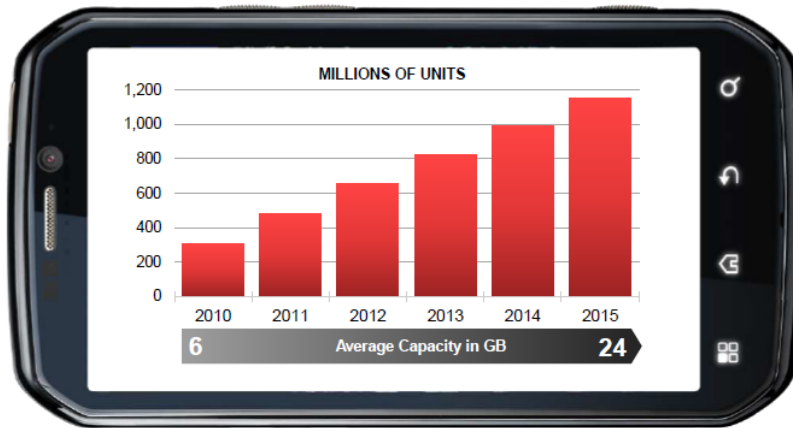
4



Courtesy of Flash Memory
And IEDM Conferences 2011

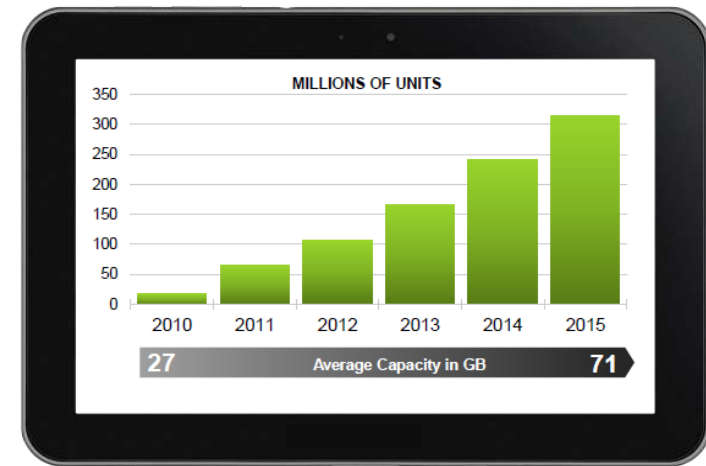


Growth Driver 1: Smartphones



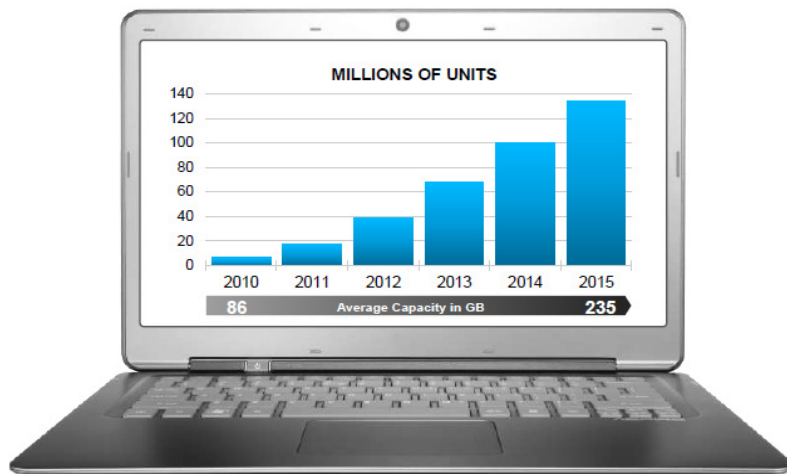
Source: Gartner December, 2011 - Forecast: Semiconductor Consumption by Electronic Equipment Type, Worldwide, 4Q11 Update

Growth Driver 2: Tablets



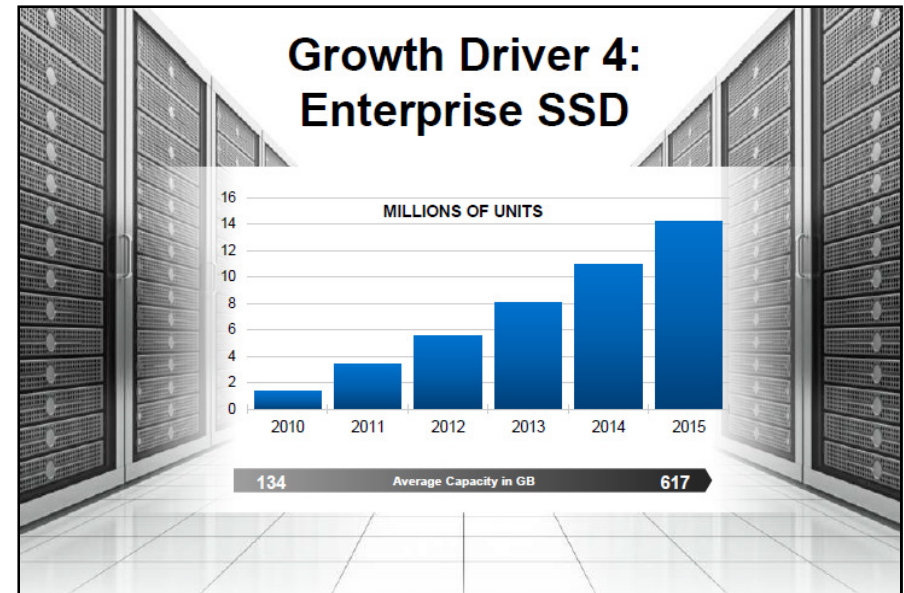
Source: Gartner December, 2011 - Forecast: Semiconductor Consumption by Electronic Equipment Type, Worldwide, 4Q11 Update

Growth Driver 3: PC SSD



Source: Gartner December, 2011 - Forecast: Semiconductor Consumption by Electronic Equipment Type, Worldwide, 4Q11 Update

Growth Driver 4: Enterprise SSD



Yole Développement sees the PCM and MRAM markets reaching \$1.6 billion in 2018

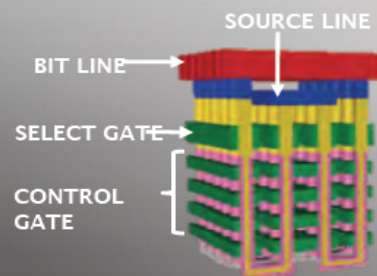
Yole Développement released a new report on Emerging Non-Volatile Memories (which include four major technologies: MRAM, PCM, RRAM and FeRAM). They see the market increasing ten-fold in the next five years to \$2 billion by 2018 (of which STT-MRAM and PCM will take the major share of \$1.6 billion) - mostly due to improved scalability and chip density.



Courtesy of Yole

Adding the 3rd Dimension: BiCS and 3D Crosspoint

BIT COST SCALABLE (BICS) 3D NAND



- > Potential to leverage existing NAND toolsets for continued cost declines
- > Electron Storage in a vertical NAND string

Source: Toshiba VLSI, 2009

3D CROSSPOINT RESISTIVE RAM 3D RRAM



- > On-gate requirement
- > Storage Channel

Source:

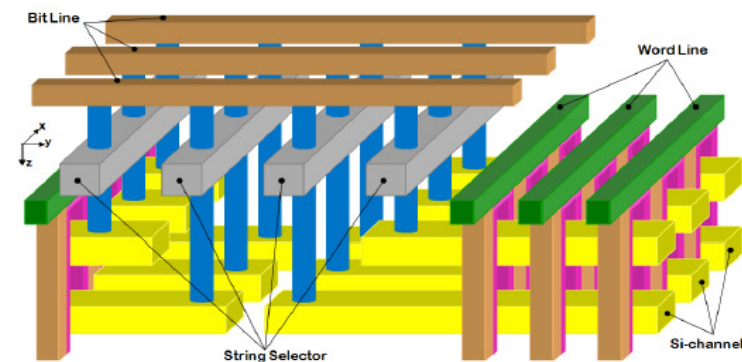
Wednesday, August 10, 2011

Courtesy of Flash Memory
And IEDM Conferences 2011



Stacked 3D Cell Structures

Hybrid Stacked 3D



3D Cell Structure with Horizontal Poly-Si Channel

[IMW 2011 by Hynix]

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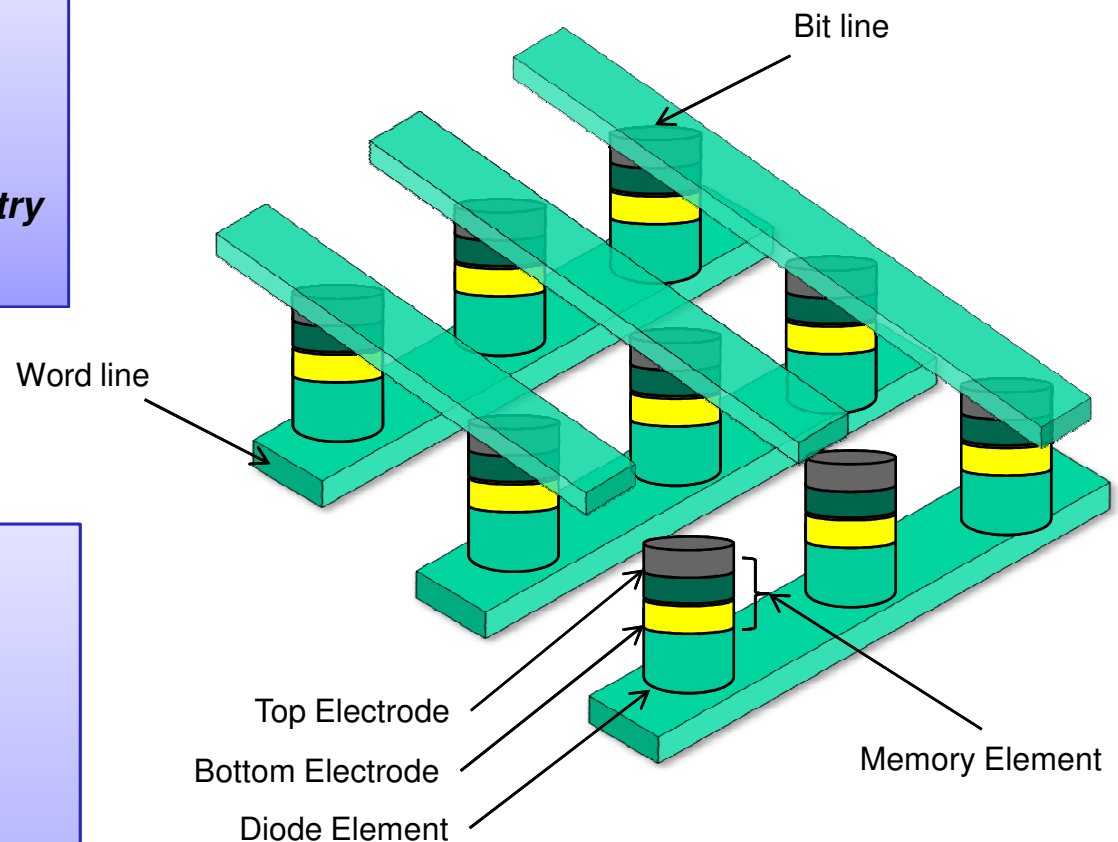
www.telefunkensemi.com

■ **Cross Point Memory (3D)**

- *Re-use of Interconnects*
- *Suitable for 3D Stacking*
- *Can be Integrated with CMOS circuitry*
- *Costs*

■ **Requirements to replace NAND**

- *Cell Size*
- *Capable of Multi-level*
- *Performance and Reliability*
- *Scalability*
- *Re-use of Fabrication Techniques*
- *Costs*

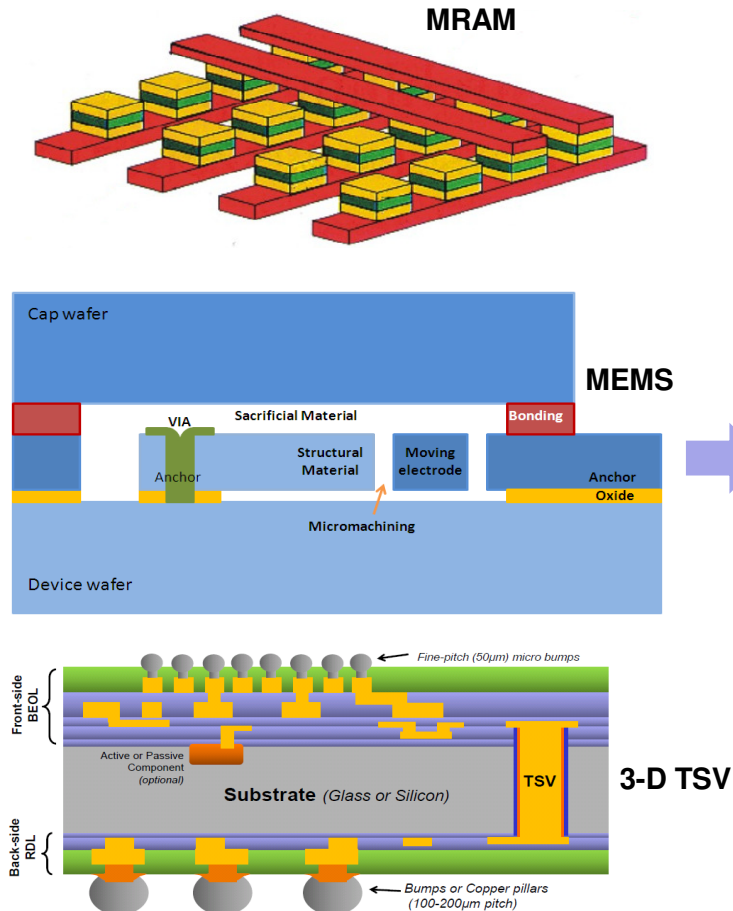


Device Type	HDD	DRAM	NAND Flash	FRAM	MRAM	STTRAM	PCRAM	NRAM
Maturity	Product	Product	Product	Product	Product	Prototype	Product	Prototype
Present Density	400Gb/in ² [7]	8Gb/chip [9]	64Gb/chip [10]	128Mb/chip	32Mb/chip	2Mb/chip	512Mb/chip	NA
Cell Size (SLC)	(2/3)F ²	6F ²	4F ²	6F ²	20F ²	4F ²	5F ²	5F ²
MLC Capability	No	No	4bits/cell	No	2bits/cell	4bits/cell	4bits/cell	No
Program Energy/bit	NA	2pJ	10nJ	2pJ	120pJ	0.02pJ	100pJ	10pJ [11]
Access Time (W/R)	9.5/8.5ms [8]	10/10ns	200/25us	50/75ns	12/12ns	10/10ns	100/20ns	10/10ns [11]
Endurance/Retention	NA	10 ¹⁶ /64ms	10 ⁵ /10yr	10 ¹⁵ /10yr	10 ¹⁵ /10yr	10 ¹⁵ /10yr	10 ⁵ /10yr	10 ¹⁵ /10yr

Device Type	RRAM	CBRAM	SEM	Polymer	Molecular	Racetrack	Holographic	Probe
Maturity	Research	Prototype	Prototype	Research	Research	Research	Product	Prototype
Present Density	64Kb/chip	2Mb/chip	128Mb/chip	128b/chip	160Kb/chip	NA	515Gb/in ²	1Tb/in ²
Cell Size	6F ²	6F ²	4F ²	6F ²	6F ²	N/A	N/A	N/A
MLC Capability	2bits/cell	2bits/cell	No	2bits/cell	No	12bits/cell	N/A	N/A
Program Energy/bit	2pJ	2pJ	13pJ	NA	NA	2pJ	N/A	100pJ [12]
Access Time (W/R)	10/20ns	50/50ns	100/20ns	30/30ns	20/20ns	10/10ns	3.1/5.4ms	10/10us
Endurance/Retention	10 ⁵ /10yr	10 ⁵ /Months	10 ⁹ /days	10 ⁴ /Months	10 ⁵ /Months	10 ¹⁶ /10yr	10 ⁵ /50yr	10 ⁵ /NA

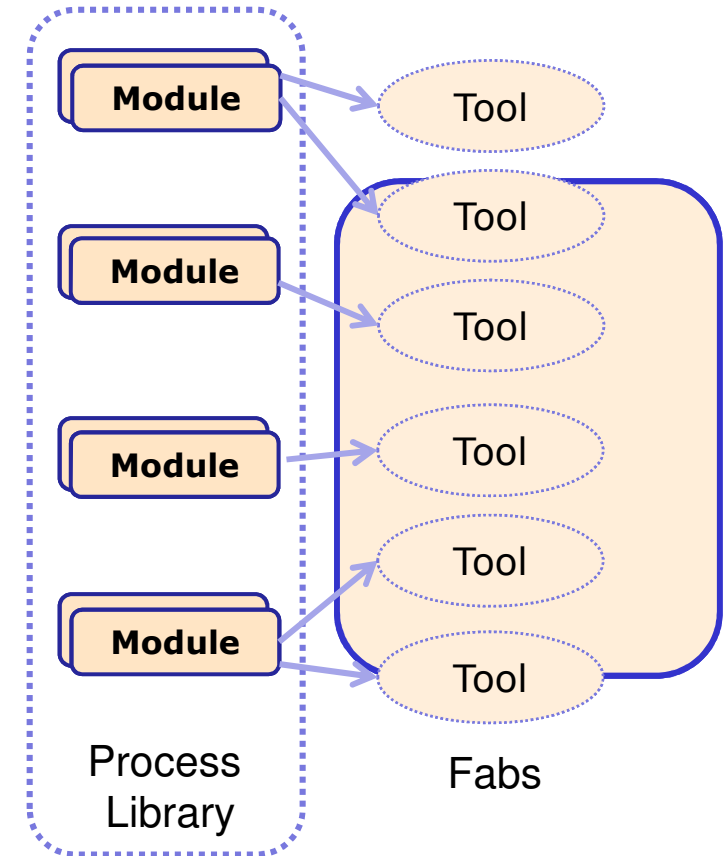
Kryder, et al. IEEE Transactions on Magnetics, Vol. 45, October 2009

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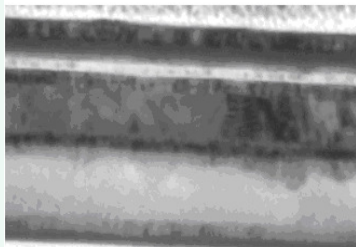
Custom Integrated Process Flow

Engineering Services



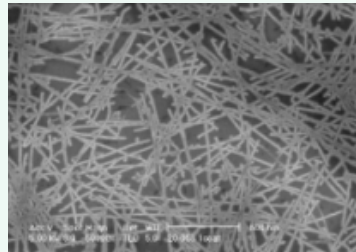
Process library, tool set and engineering expertise enable development of custom integrated process flows for novel silicon based process technologies

Material Integration



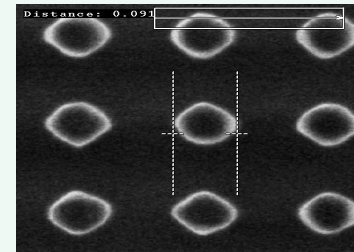
- DC, RF & Co-Sputtering
- Metals, Metal Nitrides
- Mag Stack & Anneal

Novel Materials



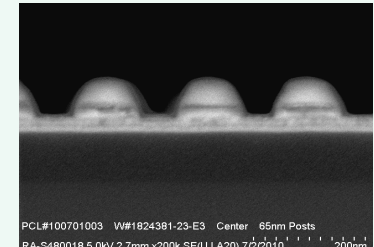
- Atomic Layer Deposition
- Metals, Oxides, Nitrides
- Carbon Nanotubes

Lithography



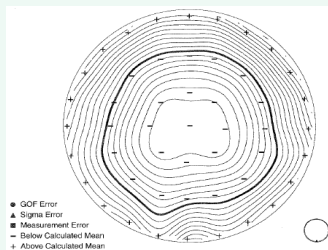
- 110nm Lithography
- DP Spacer Techniques
- <110nm L/S, 110nm Posts

Novel Etch



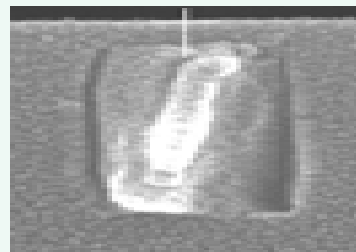
- Nobel Metals
- High Temp: 170-350C
- Physical Ion Milling

Low Temp Process



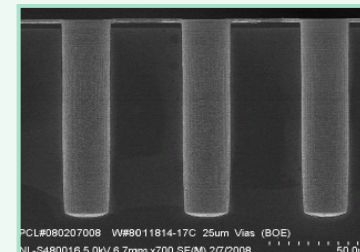
- <200C Modules
- Nitride, Oxide Films
- Ash & Cleans

CMP



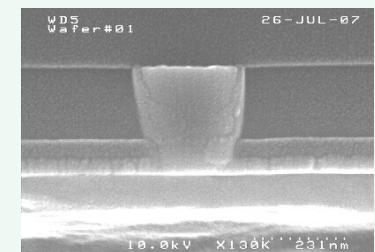
- Selective Slurries
- Oxide, Tungsten
- Exotic Materials

TSV



- DSiE
- Cu, W, Poly
- Barrier Materials

Interconnect



- Foundry CMOS
- Cu & Al interconnect
- Alignment

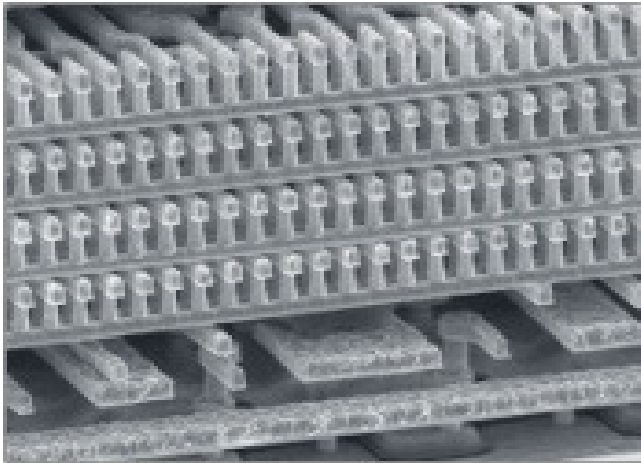
Memory Materials Development

H																	He
Li	Be											B	C	N	O	F	Ne
Na	Mg											Al	Si	P	S	Cl	Ar
K	Ca	Sc	Ti	V	Cr	Mn	Fe	Co	Ni	Cu	Zn	Ga	Ge	As	Se	Br	Kr
Rb	Sr	Y	Zr	Nb	Mo	Tc	Ru	Rh	Pd	Ag	Cd	In	Sn	Sb	Te	I	Xe
Cs	Ba	La	Hf	Ta	W	Re	Os	Ir	Pt	Au	Hg	Tl	Pb	Bi	Po	At	Rn
Fr	Ra	Ac	Rf	Db	Sg	Bh	Hs	Mt									
			Ce	Pr	Nd	Pm	Sm	Eu	Gd	Tb	Dy	Ho	Er	Tm	Yb	Lu	
			Th	Pa	U	Np	Pu	Am	Cm	Bk	Cf	Es	Fm	Md	No	Lr	

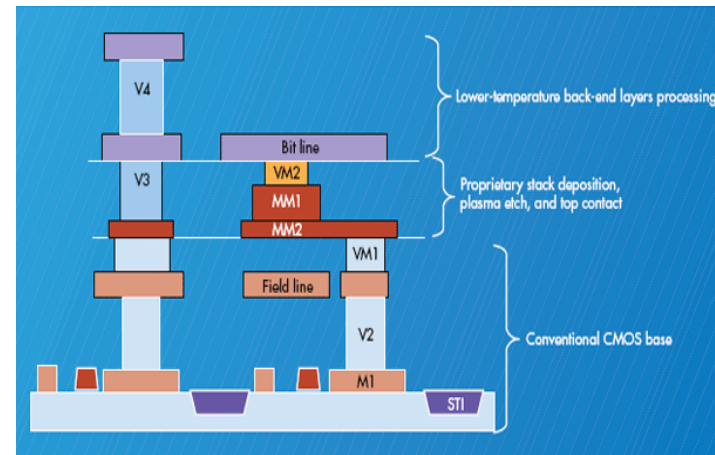
Typical CMOS Fab

Additional on TDCS Tool sets

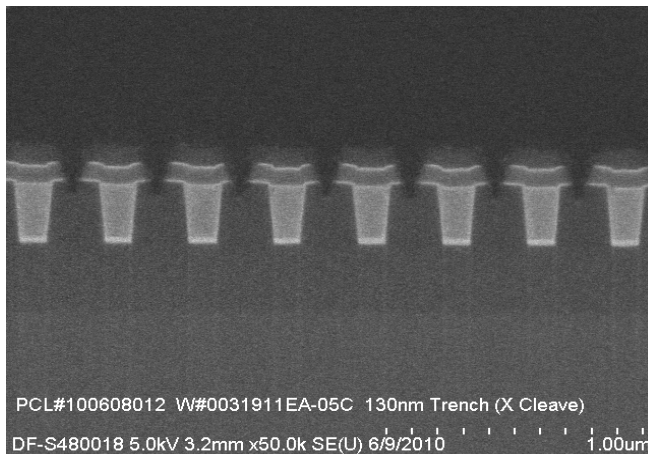
Device	Materials	Process Module's
MRAM	Co, Fe, B, Ni Ta, Ti, Pt, Mn, Ru, Mg, Ir, Al, Metal Oxides	<ul style="list-style-type: none"> Low temp processing (<200C) Nobel Etch and Cleans AlCu Interconnect Interconnect with CMOS Materials Integration CMP Hardmask and Liner Integration Double Patterning
PCRAM	Ag, GeS ₂ , GST (Ge, Sb, Te)	
ReRAM	Zr, Pr, Ca, Y, Pd, La, Complex Metal Oxides	
FeRAM	PZT (Pb, Zr, Ti, O), SBT (Sr, Bi, Ta, O), BLT (Bi, La, Ti, O)	
NRAM	CNT, W	
SQC	Nb/AlO _x /Nb, TiPt	



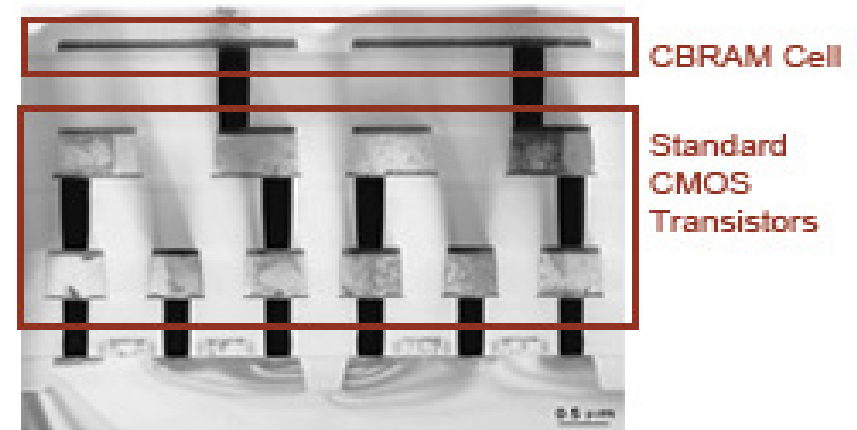
3-D Memory: Courtesy Sandisk



MRAM Memory: Courtesy Crocus



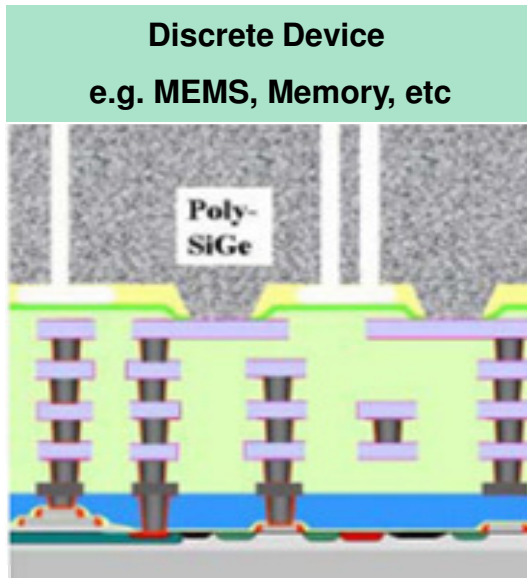
ReRAM Memory: Courtesy Company B



CBRAM Memory: Courtesy Adesto

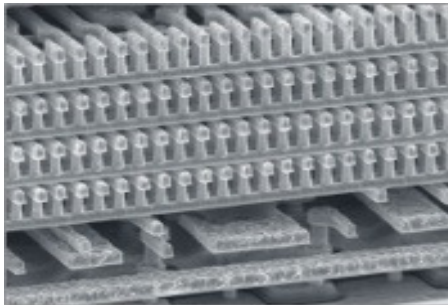
Case Example: Key Fabrication Elements

- Integration of CMOS Wafers to Memory
- Etch Integration
- Low Temperature Module Blocks
- Inter-Dielectric Planarity

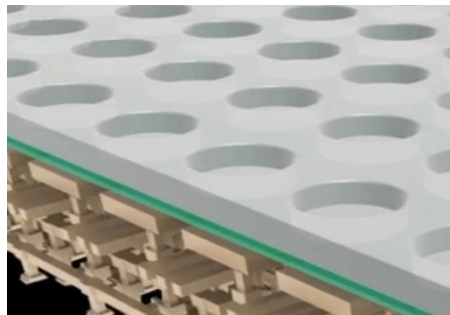


Monolithic integration of Discrete Devices and CMOS

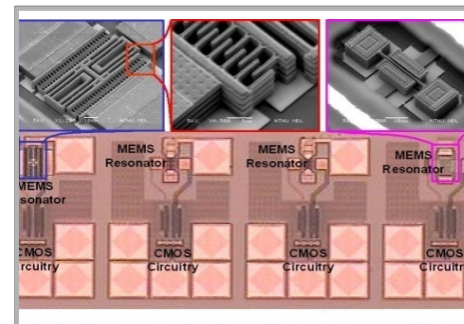
	<i>Pro</i>	<i>Con</i>
<i>Compact Solution</i>	<ul style="list-style-type: none"> ▪ Increase Chip Density ▪ Smaller Devices 	<ul style="list-style-type: none"> ▪ Integration challenges
<i>Device Performance</i>	<ul style="list-style-type: none"> ▪ Less Interconnect ▪ Minimize parasitics ▪ Improved Device Performance 	<ul style="list-style-type: none"> ▪ Challenge for devices with thermal requirements
<i>Cost</i>	<ul style="list-style-type: none"> ▪ Reduced Assembly ▪ Reduced Packaging ▪ Lower Cost of Ownership 	<ul style="list-style-type: none"> ▪ Potential Yield Mis-match between devices



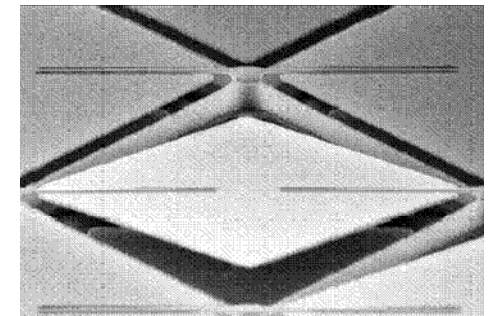
3-D Memory: Courtesy Sandisk



Lab-on-a-chip integrates microfluidics, sensors and logic to more rapidly perform gene sequencing



MEMS Resonator on CMOS used in RF domain: frequency references for oscillators, filters and mixers



Micro-Mirrors over CMOS (picture courtesy of Spatial Photonics). Sample applications include Microdisplays

- Integration of CMOS Cu Wafers to Memory
- Etch Integration
- Low Temperature Module Blocks
- Inter-Dielectric Planarity

Spin Transfer Technologies raised \$36 million to accelerate its OST-MRAM technology development

Spin Transfer Technologies (STT) announced that they raised \$36 million in series A funding led by parent company, Allied Minds and Invesco Asset Management. STT will use the money to accelerate the development of its patented orthogonal spin transfer magneto resistive random access memory technology (OST-MRAM) - by scaling operation, hiring new employees and purchasing equipment.



Toshiba designed an STT-MRAM/SRAM hybrid cache for ultra-low power processors

Toshiba has a new hybrid cache design that uses STT-MRAM and SRAM combination. This is aimed towards next-generation low-power computer processors. These new computers will usually be off, and the time and power it takes to "wake up" is considerable. The new design can reduce the energy consumption by around half - and does not effect processing capacity.

Micron and A*STAR to jointly develop high density STT-MRAM

Micron and the A*STAR Data Storage Institute (DSI) from Singapore announced that they will jointly develop STT-RAM. The two companies will invest in a 3-year joint-research program to develop high-density STT-MRAM devices.

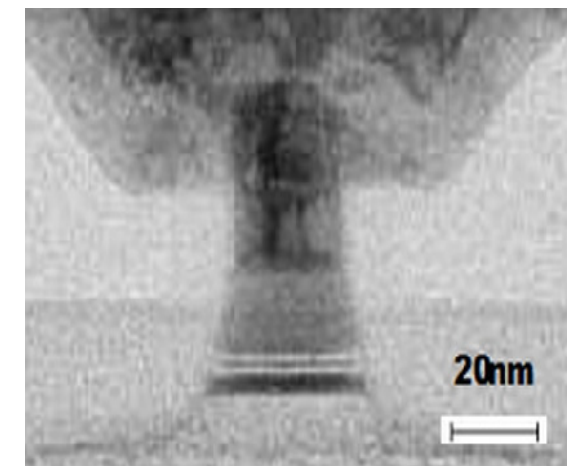
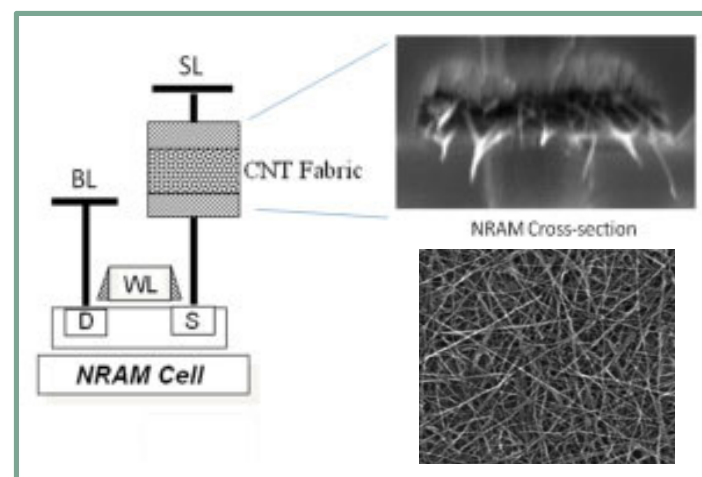
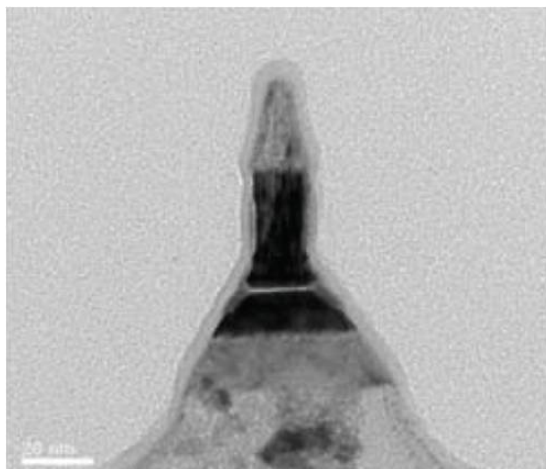
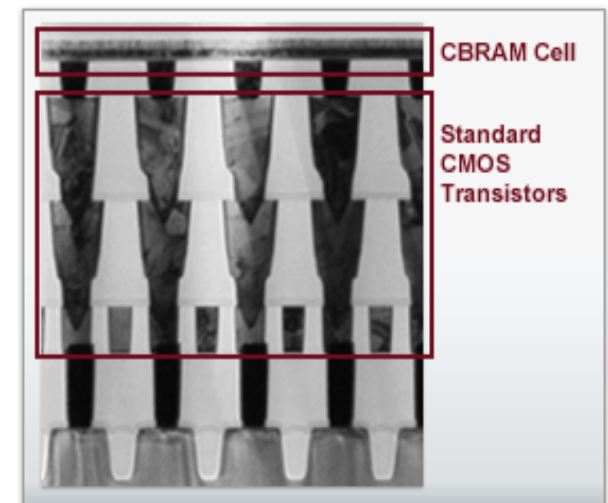
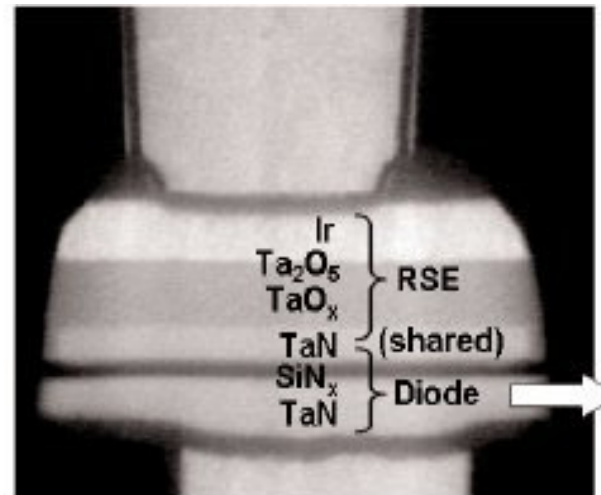
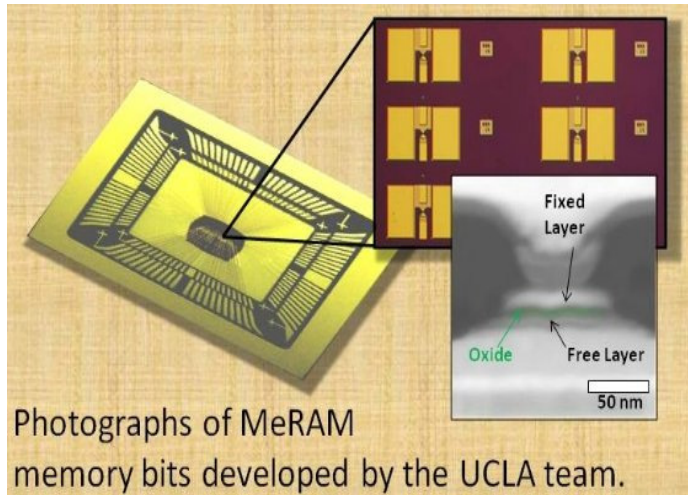
Toshiba and Hynix to co-develop and produce MRAM products

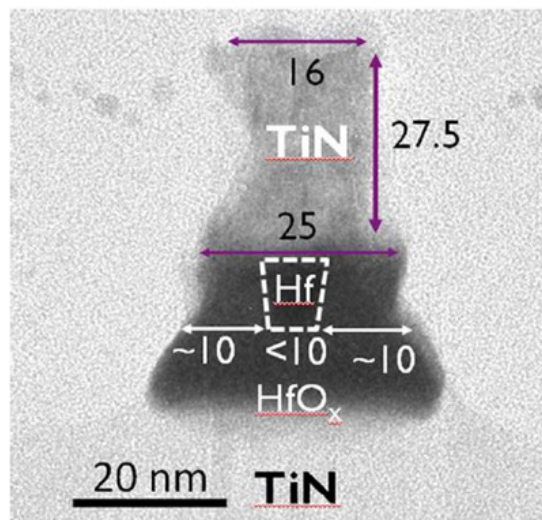
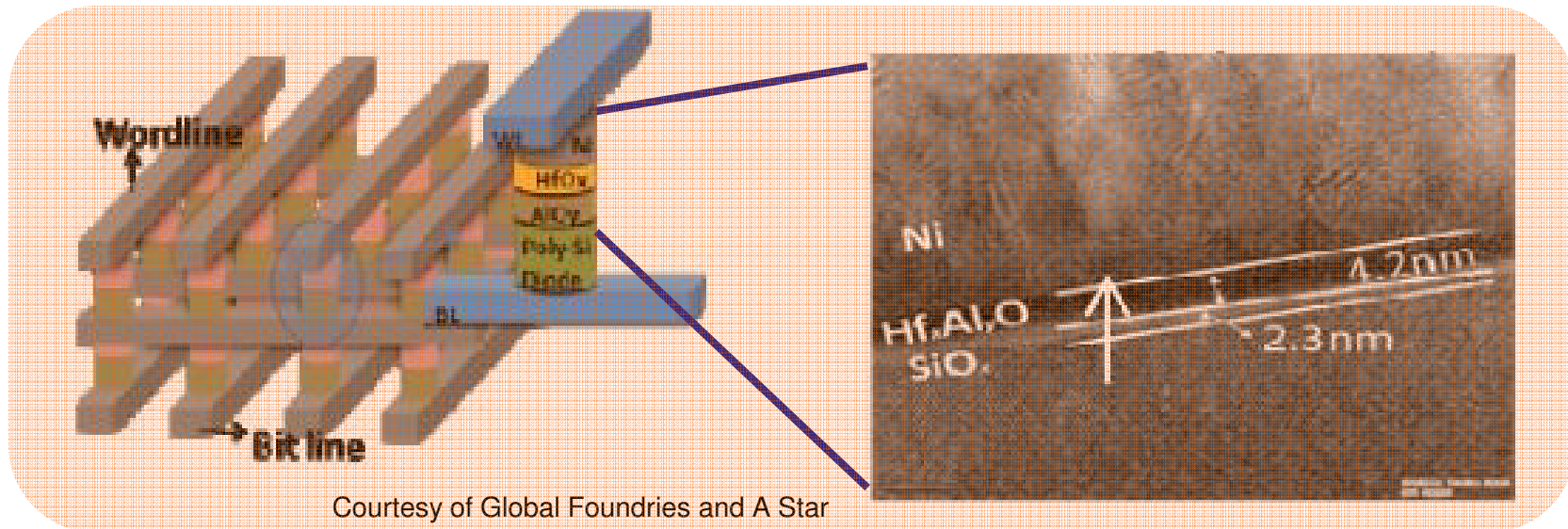
Toshiba and Hynix announced an agreement to jointly develop MRAM products. Once the development is complete, the companies intend to establish an MRAM production plant together. We believe the companies intend to develop STT-MRAM technology.



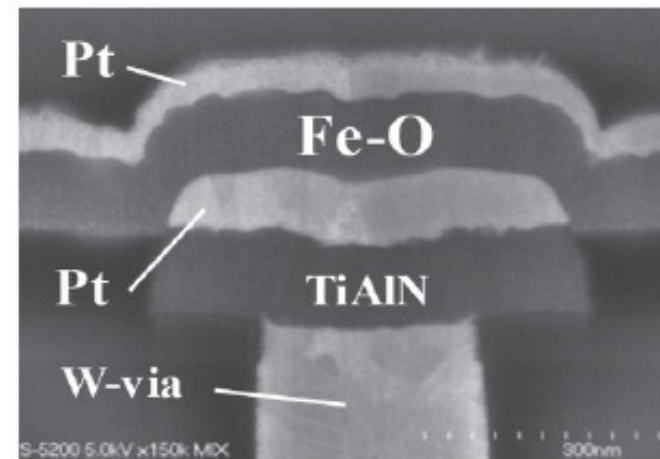
UCLA receives \$5.5 million to continue STT-RAM research

UCLA has been awarded \$5.5 million from DARPA to continue develop STT-MRAM technologies. This is the second grant for this project, which brings the total DARPA grants to \$10.5 million. The first stage has been completed a year early than planned - by meeting (and in fact significantly surpassing) speed, energy consumption and stability requirements of their STT-RAM (write times smaller than 5 nanoseconds and write energies lower than 0.25 picojoules per bit).





Courtesy of IMEC



ReRAM Cell Using FeO Variable Resistance
Cross-section of the ReRAM memory cell prototyped by Matsushita Electric Industrial. Top and bottom electrodes are Pt.

***Large Variation in Materials and Thicknesses,
not one Etch Solution that fits all applications***

**Stack Thickness
500A to 1000A**

Memory	Thickness (A)
Ta	100 - 500A
CoFeB	30A
MgO	15A
Ru	10A – 60A
CoFe	40A
PtMn	125A
GST	500A
Ag	--
La	--

**Stack Thickness
1000A to 2.2um**

Life Sciences	Thickness (A)
Ta	50A
Ru	10A - 20A
NiFe	20A
CoFe	475A

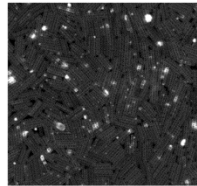


FIG. 45



FIG. 46c

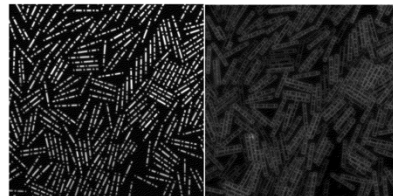
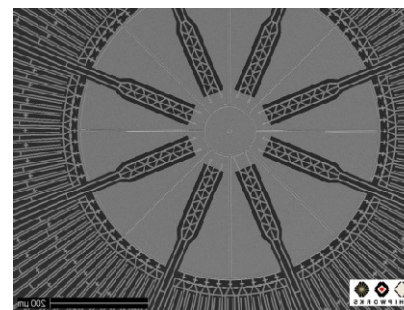


FIG. 46a

FIG. 46b

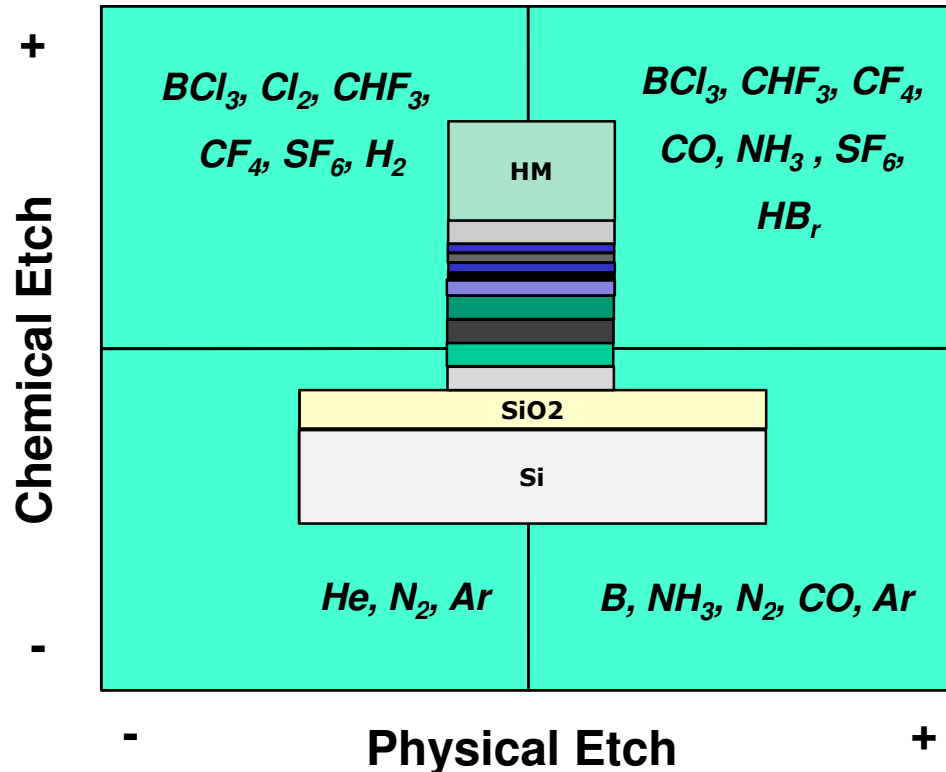
**Stack Thickness
1000A to 1.4um**

MEMS Compass	Thickness (A)
Co	500A
CoNi	600A
Ni	1000A
NiFe	500A
Al	10kA



**Stack Thickness
500A to 2.2um**

Other	Thickness (A)
Pt	1000A
PZT	Up to 2.2um
Nb	--



Pressure Ranges	
Etch Types	Torr
Ion Milling	$10^{-4} - 10^{-3}$
Reactive Ion Etch	$10^{-3} - 10^{-1}$
Plasma Etch	$10^{-1} - 5$

<100 mTorr

Higher Energy

Physical Etch (Sputtering)

- Physical momentum transfer
- Anisotropic etch profile
- Low etch rate
- Poor selectivity
- Radiation damage possible

RIE (Reactive Ion Etch)

- Physical(ion) and chemical
- Anisotropic, controllable etch profile
- More selective than sputtering

Plasma Etching

- Chemical, thus faster by 10-1000X
- Isotropic etch profile
- High etch rate
- Good selectivity
- Less prone to radiation damage

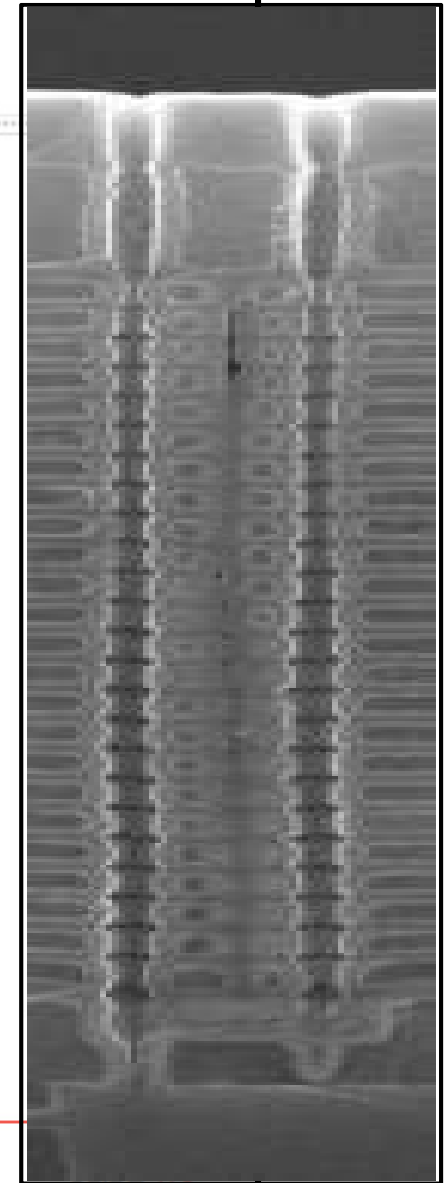
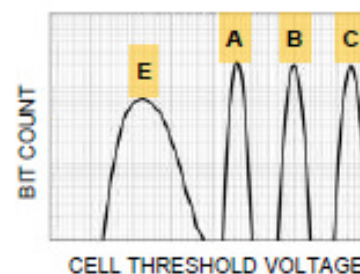
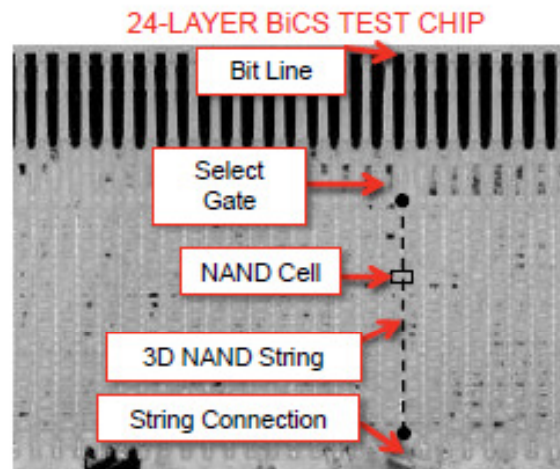
Higher Pressure



	LAM 9600	AMAT DPS2	Tegal 6540	Veeco Ion Mill
Gases Available	<p>Chamber A (60C): BCl₃, Cl₂, Ar, N₂, O₂, SF₆, He, O₂</p> <p>Chamber B (250C): DSQ O₂, H₂O</p>	<p>Chamber A (250C): BCl₃, Cl₂, Ar</p> <p>Chamber B (65C): CF₄, HeO₂, HBr, Cl₂</p>	<p>HRe 2.1 (30-80C): BCl₃, Cl₂, CHF₃, CF₄, Ar, O₂</p> <p>HRe 4.0 (170-350C): CO, Cl₂, NH₃, CF₄, Ar, O₂</p>	<p>Single Chamber: Ar</p>
Materials Etched	<p>Al, TiN/Al/Ti, TiW/TiAl, GST</p>	<p>Chamber A: High-k, Al₂O₃, TiN, TaN, Ru</p> <p>Chamber B: Metal Gate Stacks - Poly & metal alloys</p>	<p>HRe 2.1: Oxide, Ti, TiN, W, Ta, GST</p> <p>HRe 4.0: Ti, TiN, Nb, Pt, AlO_x, Ta, PtMn, CoFe, MgO, Ru, Ag</p>	<p>Oxide, Ti, TiN, W, Ag, CoFe</p>

Update on BiCS 3D NAND

- VERTICAL 3D NAND STRING STRUCTURE
- UTILIZES EXISTING WAFER FAB INFRASTRUCTURE
- DOES NOT NEED EUV
- KEY DEVELOPMENTS
 - 24-layer array development vehicle
 - Multi-level cell (MLC) functionality shown
- BRIDGE TO 3D ReRAM



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ANALYST DAY || FEBRUARY 16, 2012

- We continue to see innovative and disruptive materials development for next generation NVM technologies
- The challenge for NVM developers is to find a suitable replacement for existing NAND performance for capacity, performance, reliability and costs
- TDCS offers a comprehensive set of capabilities to develop and integrate Novel Memory technologies
- There will be one winner (or more), but it's still in the validation stage!

Thank You

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